

#2/105

Sheet 1 of 2

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Docket No. 0756-2332		Serial No. Not Yet Assigned	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)							
				Applicant: Takeshi FUKADA et al.			
				Filing Date: July 16, 2001		Group: 2825	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
ABM	5,372,860	12/13/1994	Fehlner et al.	427	578		
ABM	4,399,015	08/16/1983	Endo et al.	204	192R.26		
ABM	4,959,136	09/25/1990	Hatwar	204	192.15		
ABM	4,824,712	04/25/1989	Falleroni et al.	428	137		
ABM	5,163,220	11/17/1992	Zeto et al.	29	846		
ABM	5,094,966	03/10/1992	Yamazaki	437438	30 287		
ABM	5,296,653	03/22/1994	Kiyota et al.	174	250		
ABM	5,073,451	12/17/1991	Iida et al.	—	—		
ABM	4,985,312	01/15/1991	Furuya et al.	—	—		
ABM	5,304,518	04/19/1994	Sunahara et al.	—	—		
ABM	5,492,843	02/20/1996	Adachi et al.	437438	30 479		
ABM	5,254,208	10/19/1993	Zhang	—	—		
ABM	5,262,654	11/16/1993	Yamazaki	—	—		
ABM	5,252,140	10/12/1993	Kobayashi et al.	—	—		
ABM	4,100,330	07/11/1978	Donley	55428	60:6.429		
ABM	5,165,972	11/24/1992	Porter	55428	60:8 1.32		
ABM	4,116,658	09/26/1978	Sano	65	60:2 42		
ABM	5,480,818	01/02/1996	Matsumoto et al.	437438	30 150		
ABM	4,803,183	02/07/1989	Schwetz et al.	501	98.98.4		
ABM	5,475,264	12/12/1995	Sudo et al.	257	723		
ABM	5,485,019	01/16/1996	Yamazaki et al.	257	57		
Examiner <i>ABM Malsam</i>			Date Considered <i>1-12-2003</i>				
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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		Filing Date: July 16, 2001	Group: 2825

U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>APM</i>	5,583,369	12/10/1996	Yamazaki et al.	—	—	
<i>APM</i>	4,435,513	03/1984	Komeya et al.	—	—	
<i>APM</i>	4,478,785	10/1984	Huseby et al.	—	—	
<i>APM</i>	4,963,701	10/1990	Yasumoto et al.	—	—	
<i>APM</i>	5,674,304	10/07/1997	Fukuda et al.	—	—	
<i>APM</i>	5,929,487	07/27/1999	Fukuda et al.	—	—	

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	Document Number	Date	Country	Class	Subclass	Translation Yes No
<i>APM</i>	59-121876	07/14/1984	Japan	—	—	Abstract
<i>APM</i>	2-102150	04/13/1990	Japan	—	—	Yes
<i>APM</i>	58-114037	07/07/1983	Japan	—	—	Abstract
<i>APM</i>	64-32443	02/02/1989	Japan	—	—	Abstract
<i>APM</i>	1-319682	12/25/1989	Japan	—	—	Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>APM</i>	K. Etemadi, "Thermal Plasma Crystal Growth", 1989 IEEE International Conference on Plasma Science, May 22-24, 1989, pp. 115.
<i>APM</i>	Hickernell et al., "The Structural and Acoustic Properties of Sputtered Aluminum Nitride on Silicon", Proceedings of the Ninth IEEE International Symposium on Applications of Ferroelectrics, August 7-10, 1994, pp. 543-546.

Examiner <i>APM</i>	Date Considered <i>1-12-2002</i>
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